


<b>Search Notes</b> 	<b>Application/Control No.</b> 10541240	<b>Applicant(s)/Patent Under Reexamination</b> OUCHI, TOSHIHIKO
	<b>Examiner</b> RYAN LEPISTO	<b>Art Unit</b> 2883

SEARCHED			
Class	Subclass	Date	Examiner
385	4, 8, 12, 40, 41, 45	11/19/08	RAL
359	331, 332	11/19/08	RAL
250	358.1, 393, 227.12	11/19/08	RAL

SEARCH NOTES			
Search Notes		Date	Examiner
See search history - EAST (all databases), non-patent literature (IEEE, OpticsInfoBase)		11/19/08	RAL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--